

# PhD in Smart Computing Progress Report - 1st year

Tommaso Papini

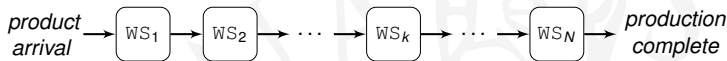
Department of Information Engineering, University of Florence, Italy  
tommaso.papini@unifi.it

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- ▶ Analysis of assembly lines
- ▶ A hybrid technique for MRP transient analysis
- ▶ Other projects
  - ▶ the LINFA project
  - ▶ Activity Recognition for Ambient Assisted Living
- ▶ Research plan for the next year

# Analysis of assembly lines

## Assembly line

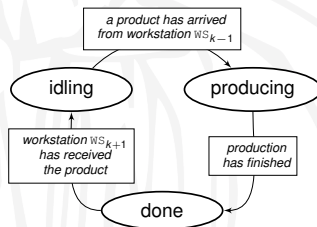


$N$  sequential workstations  $WS_1, \dots, WS_N$

- ▶ with transfer blocking
- ▶ and no buffering capacity

Workstation  $WS_k$  can be in one of three states

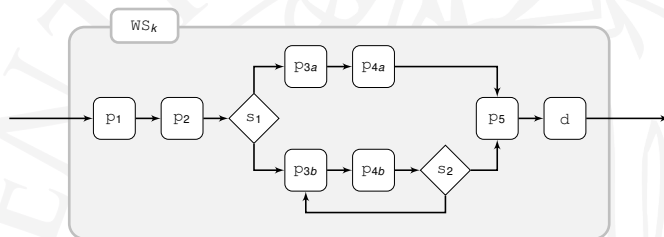
- ▶ *producing*:  $WS_k$  is working on a product
- ▶ *done*:  $WS_k$  is done working on a product
- ▶ *idling*:  $WS_k$  is waiting for a new product



## Workstation

Each workstation  $WS_k$

- ▶ has no internal parallelism
  - ▶ at most one item being processed in each workstation
- ▶ can implement complex workflows
  - ▶ sequential/alternative/cyclic phases with random choices
- ▶ and has GEN phases' durations



The last phase has no duration and encodes the *done* state

## Underlying stochastic process

The underlying stochastic process of each isolated workstation is a Semi Markov Process (SMP)

- ▶ due to GEN durations
- ▶ and the absence of internal parallelism

The whole assembly line finds a renewal in any case where

- ▶ every *done* station is in a queue before a bottleneck
- ▶ and everything else is *idling*



## Inspection with partial observability

The assembly line can be inspected by external observers

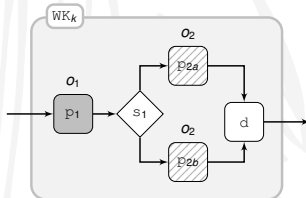
- ▶ the line can be considered at steady-state at inspection
- ▶ there can be ambiguity about the current phase

An observation is a tuple  $\omega = \langle \omega_0, \omega_1, \dots, \omega_N \rangle$

- ▶  $\omega_0$  indicates if a new product is ready to enter the line or not
- ▶  $\omega_k = \langle \sigma_k, \phi_k \rangle$  refers to  $WS_k$ 
  - ▶  $\sigma_k$  indicates if  $WS_k$  is *idle/producing/done*
  - ▶  $\phi_k$  identifies the set of possible current phases

Two kinds of uncertainty

- ▶ about the actual current phase
  - ▶ discrete
- ▶ about the remaining time in the current phase
  - ▶ continuous



## Performance measures

### Time To Done

- ▶ The remaining time until workstation  $k$ , according to observation  $\omega$ , reaches the *done* state



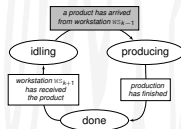
### Time To Idle

- ▶ The remaining time until workstation  $k$ , according to observation  $\omega$ , reaches the *idling* state



### Time To Start Next

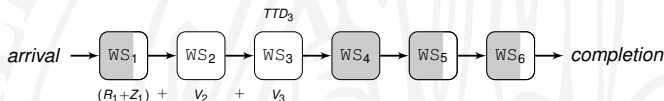
- ▶ The remaining time until workstation  $k$ , according to observation  $\omega$ , starts the production of a new product



## Time To Done

$$\text{TTD}(k, \omega) := \begin{cases} \sum_{\gamma \in \phi_k} P_{k, \gamma, \omega} \cdot (R(k, \gamma) + Z(k, \gamma)), & \text{if } \sigma_k = \textit{producing} \\ \text{TTD}(k-1, \omega) + V(k), & \text{if } \sigma_k = \textit{idling} \\ 0, & \text{if } \sigma_k = \textit{done} \end{cases}$$

- ▶  $P_{k, \gamma, \omega}$  probability weight that  $\text{WS}_k$  is in phase  $\gamma$  according to  $\omega$
- ▶  $R(k, \gamma)$  remaining time in phase  $\gamma$  of  $\text{WS}_k$
- ▶  $Z(k, \gamma)$  execution time of phases of  $\text{WS}_k$  that follow  $\gamma$
- ▶  $V(k)$  production time of  $\text{WS}_k$



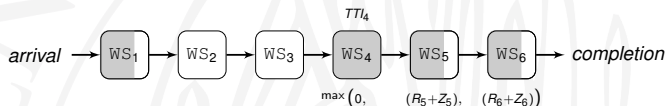
Backward recursive evaluation



## Time To Idle

$$TTI(k, \omega) := \begin{cases} \max\{TTD(k, \omega), TTI(k+1, \omega)\}, & \text{if } \sigma_k \in \{\text{producing, done}\} \\ 0, & \text{if } \sigma_k = \text{idling} \end{cases}$$

- ▶  $TTI(k, \omega) = \max\{TTD(k, \omega), \dots, TTD(k+n, \omega)\}$ 
  - ▶  $WS_j$  producing/done  $\forall j \in [k, k+n]$
  - ▶ either  $WS_{k+n}$  last workstation or  $WS_{k+n+1}$  idling
- ▶  $WS_k$  becomes idle when the bottleneck finishes its production

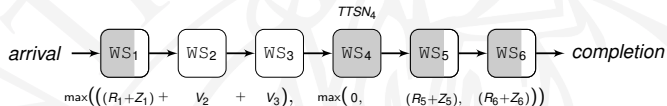


Forward recursive evaluation

- └ Analysis of assembly lines
- └ Evaluation of performance measures

## Time To Start Next

$$TTSN(k, \omega) := \max\{TTI(k, \omega), TTD(k-1, \omega)\}$$



Forward and backward recursive evaluation

## Disambiguation of observed phases

Resolve observed (producing) phases' ambiguity

- ▶ steady-state probability that  $WS_k$  is in phase  $\gamma$  according to  $\omega$

Given observation  $\phi_k$  for workstation  $WS_k$

- ▶ we compute probability  $P_{k,\gamma,\omega}$
- ▶ that it was actually  $\gamma$  that produced  $\phi_k$

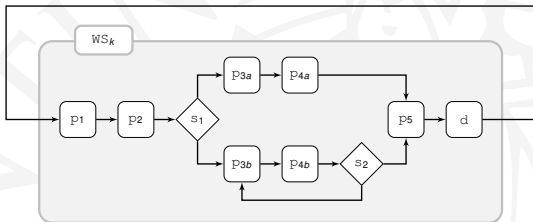
$$P_{k,\gamma,\omega} = \frac{\tilde{\pi}(\gamma)}{\sum_{\gamma' \in \phi_k} \tilde{\pi}(\gamma')}$$

- ▶  $\tilde{\pi}(\gamma)$  steady-state probability of phase  $\gamma$  in an isolated model of  $WS_k$

## Isolated workstation model

The isolated workstation model represents a workstation repeatedly processing a product

- ▶ one product being processed
- ▶ after its production, it's moved back to the entry point of the workstation



It can be used for two reasons

- ▶ steady-state probabilities of producing phases are independent
- ▶ the inspection is at steady-state
  - ▶ arrivals and productions can be considered in equilibrium

- └ Analysis of assembly lines
- └ Evaluation of performance measures

## Remaining time

Evaluation of  $F_{R(k,\gamma)}(t)$  = CDF of  $R(k,\gamma)$

- ▶  $R(k,\gamma)$  *remaining time* in phase  $\gamma$  of  $WS_k$

Problem!

- ▶ remaining times of enabled GEN transitions are *dependent*
- ▶ joint probabilities don't allow for a compositional approach

1/3 *Immediate* approximation

- ▶ assume that phase  $\gamma$  is inspected at its ending
  - ▶  $\tilde{F}_{R(k,\gamma)}(t) = 1 \quad \forall t$
- ▶ represents an *upper bound*

2/3 *Newly enabled* approximation

- ▶ assume that phase  $\gamma$  is inspected at its beginning
  - ▶  $\tilde{F}_{R(k,\gamma)}(t) = F_\gamma(t)$
  - ▶  $F_\gamma(t)$  original CDF of the duration of  $\gamma$
- ▶ represents a *lower bound*

## Remaining time

### $\frac{3}{3}$ *Independent remaining times approximation*

- ▶ consider the remaining times of ongoing phases as *independent*
- ▶ represents a (better) *lower bound*

### Theorem: positive correlation & stochastic order

If  $\hat{R}$  is an independent version of vector  $R$  of positively correlated remaining times of ongoing phases, then  $\hat{R} \geq_{st} R$

Steady-state distribution of  $\hat{R}(k, \gamma)$

computed according to the Key Renewal Theorem<sup>1</sup>

$$\tilde{F}_{R(k, \gamma)}(t) = \frac{1}{\mu} \int_0^t [1 - F_\gamma(s)] ds$$

- ▶  $\mu$  expected value of  $F_\gamma(t)$

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<sup>1</sup>Serfozo, R., 2009. Basics of applied stochastic processes. Springer Science & Business Media.

- └ Analysis of assembly lines
- └ Evaluation of performance measures

## Execution and production time

Evaluation of  $F_{Z(k,\gamma)}(t)$  and  $F_{V(k)}$

- ▶  $Z(k, \gamma)$  *execution time* of phases of  $WS_k$  that follow  $\gamma$
- ▶  $V(k)$  *production time* of  $WS_k$

CDFs of  $Z(k, \gamma)$  and  $V(k)$  are computed as transient probabilities

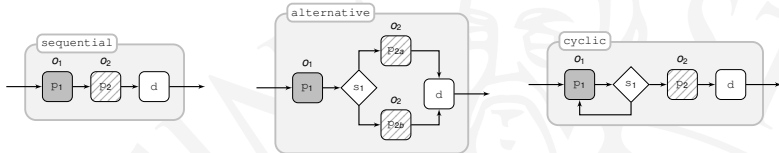
- ▶  $F_{Z(k,\gamma)}$  transient probability from phase after  $\gamma$  to final phase of  $WS_k$
- ▶  $F_{V(k)}$  transient probability from first phase to final phase of  $WS_k$

Upper/lower bounds for  $TTD$ ,  $TTI$  and  $TTSN$  can be evaluated

- ▶ *convolution* and *max* operations maintain stochastic order

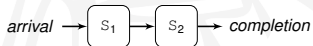
## Case study assembly lines

### Sequential, alternative and cyclic workstations



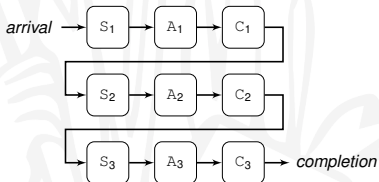
#### Simple assembly line

- ▶ two sequential workstations
- ▶ both in phase  $p_1$  at inspection



#### Complex assembly line

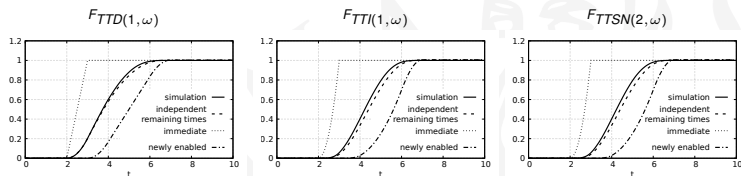
- ▶ three repetitions
- ▶ of sequential/alternative/cyclic ws
- ▶ all observed in *producing*





## Simple assembly line

TTDone, TTIdle, TTStartNext



$TTD$ ,  $TTI$  and  $TTSN$  computed in

- ▶ 41/45/42 min for simulation
- ▶ 0.15/0.18/0.10 s for bounds

Very good approximation results

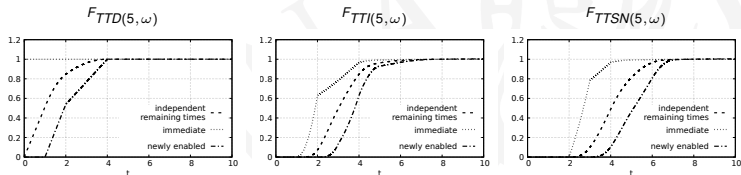
- ▶ especially for *independent remaining times*

Feasible approach

- ▶ very fast bounds evaluation
- ▶ compared to simulation

## Complex assembly line

$TTDone$ ,  $TTIdle$ ,  $TTStartNext$



$TTD$ ,  $TTI$  and  $TTSN$  computed in

- ▶ 0.126/0.123/0.75 s for bounds

Scalable solution

- ▶ in a complex scenario
- ▶ simulation would be infeasible

# A hybrid technique for MRP transient analysis

## A hybrid technique for MRP transient analysis

Transient analysis of Markov Regenerative Processes (MRP) employing different techniques for different regenerative epochs

The basics:

- ▶ Exact techniques require specific conditions to be met
  - ▶ different techniques require different conditions
- ▶ Kernel rows of different epochs can be evaluated independently

The idea:

- ▶ Evaluate each kernel row with a different technique
  - ▶ corresponding to the condition enabled in that epoch
  - ▶ eventually with an approximate technique, if no conditions are met
- ▶ Compute transient probabilities with Markov Renewal Equations

## Techniques for MRP transient analysis

### Analysis under enabling restriction<sup>2</sup>

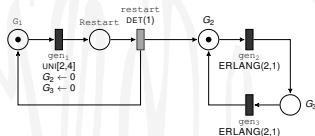
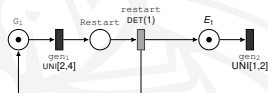
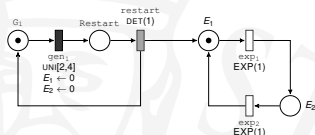
- ▶ at most one GEN enabled in each state

### Analysis with stochastic state classes<sup>3</sup>

- ▶ a regeneration is always reached within a bounded number of events
  - ▶ i.e. no cycles without regenerations
- ▶ a.k.a. bounded regeneration

### Approximate analysis

- ▶ usable when no conditions are met



<sup>2</sup>German, R., Logothetis, D., & Trivedi, K. S. (1995, October). Transient analysis of Markov regenerative stochastic Petri nets: A comparison of approaches. In Petri Nets and Performance Models, 1995., Proceedings of the Sixth International Workshop on (pp. 103-112). IEEE.

<sup>3</sup>Horváth, A., Paolieri, M., Ridi, L., & Vicario, E. (2012). Transient analysis of non-Markovian models using stochastic state classes. Performance Evaluation, 69(7), 315-335.

- └ A hybrid technique for MRP transient analysis
- └ Classification of epochs

## Classification of epochs

Through **non-deterministic analysis**

- ▶ State Class Graphs (SCG) are built
- ▶ for each regenerative epoch

By visiting each SCG, epochs are classified

- ▶ enabling restriction
  - ▶ if at most one GEN is enabled in any state
- ▶ bounded regeneration
  - ▶ if no cycle is present

- └ A hybrid technique for MRP transient analysis
- └ Iterative approximate technique

## Iterative approximate technique

Based on analysis with stochastic state classes

- ▶ truncated after enough precision is met

Improvement with heuristics

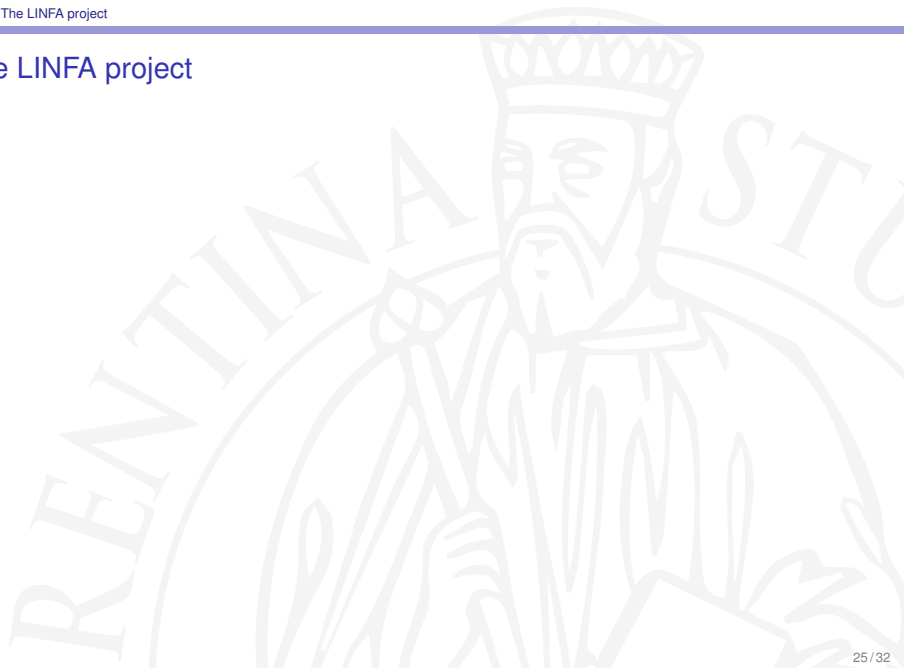
1. expand at most  $\nu_{start}$  nodes for non restricted epochs
2. identify the truncated node  $\Phi$  with highest reaching probability
  - ▶ based on steady-state analysis of the embedded DTMC
3. expand at most  $\nu_{iter}$  nodes from  $\Phi$
4. if at least  $\nu_{max}$  nodes expanded, stop
  - ▶ otherwise, return to step 2

## Other projects

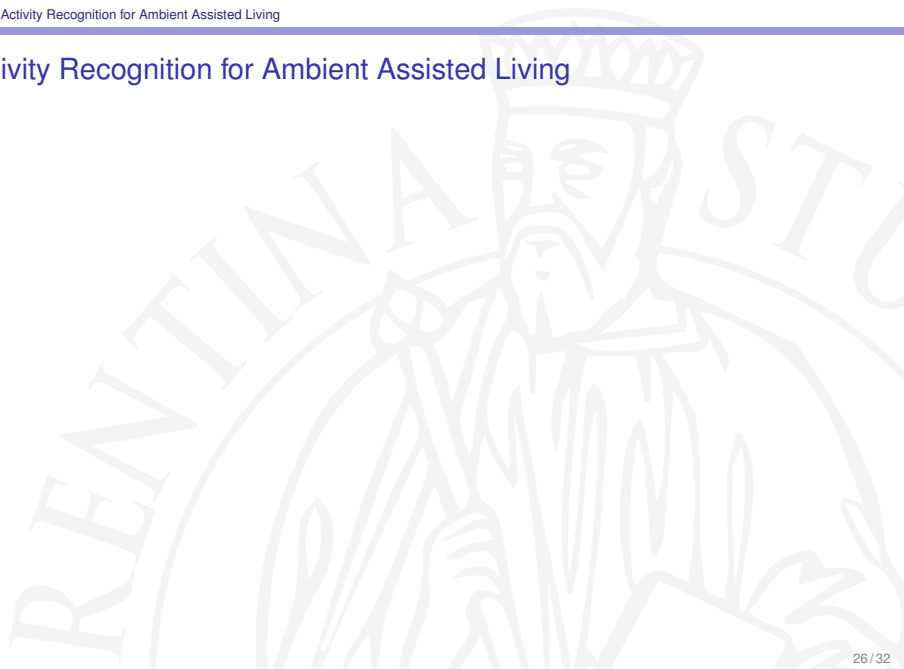


- └ Other projects
- └ The LINFA project

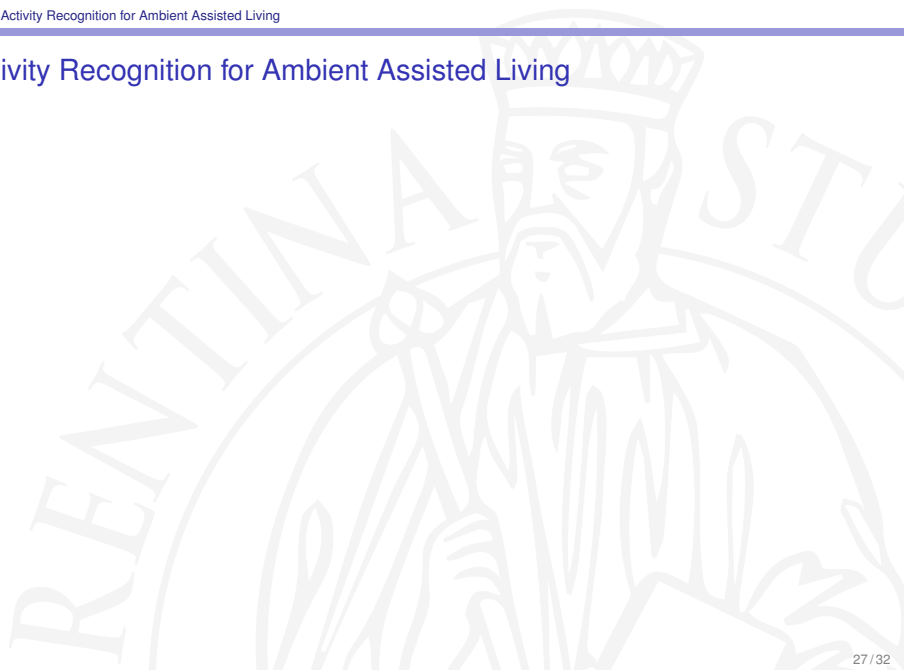
## The LINFA project



## Activity Recognition for Ambient Assisted Living

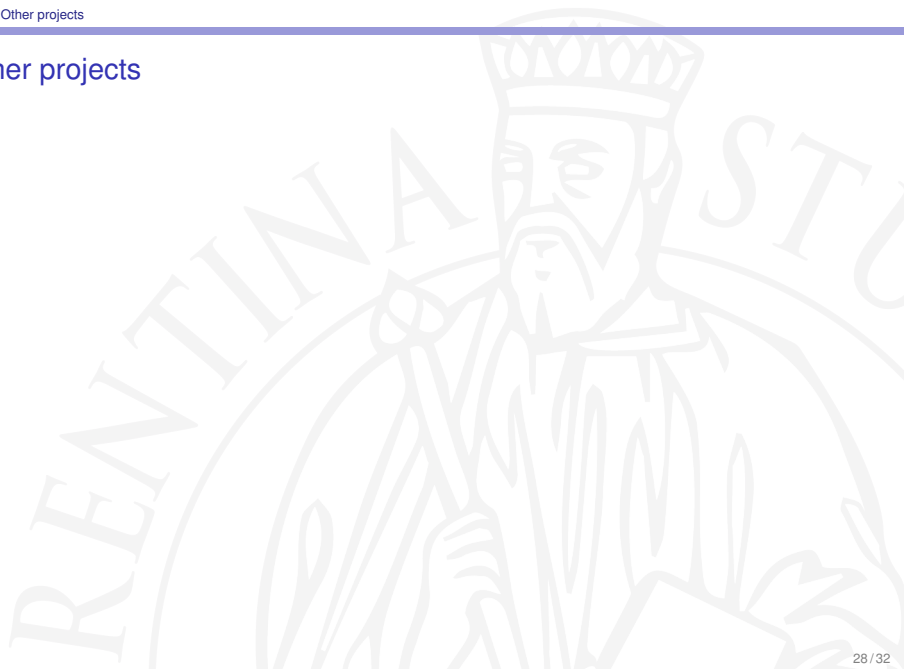


## Activity Recognition for Ambient Assisted Living



- └ Other projects
- └ Other projects

## Other projects



## Research plan for the next year

- └ Research plan for the next year
- └ Analysis of assembly lines

## Research plan for the next year

### Analysis of assembly lines

#### Introduction of buffering capacity

- ▶ with fixed/variable capacity
- ▶ so to model more realistic scenarios

#### Derivation of additional performance measures

- ▶ in the same compositional fashion
- ▶ e.g. production time of a certain product in the line
- ▶ or of the next  $N$  products

#### Derivation of a more educated *upper bound*

## Research plan for the next year

### The LINFA project

#### Model more aspects to refine the ward model

- ▶ introduce personalised healthcare protocols
- ▶ employ process mining techniques

#### State-space optimisation

- ▶ avoid state-space explosion
- ▶ investigate other tools
  - ▶ Storm

## Research plan for the next year

### Activity Recognition for Ambient Assisted Living

#### Refine model based AR

- ▶ exploit fuzzy logic to include support for continuous sensors
  - ▶ accelerometer/thermometer/...

#### Identify good AR datasets for AAL

- ▶ investigate the literature
- ▶ generate new datasets

In order to apply process mining techniques